Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/661,852	RAGHUNATH ET AL.
Examiner	Art Unit
Ellen C. Tran	2134

	SEAR	CHED	
Class	Subclass	Date	Examiner
713	156	2/10/2007	ECT
726	20	2/10/2007	ECT
726	9	2/10/2007	ECT
726	10	2/10/2007	ECT

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	2/10/2007	ECT		
NPL - IEEE XPLORE	2/10/2007	ECT		
INVENTOR SEARCH - PALM	2/10/2007	ECT		
All claims were review for 101 rejections	2/10/2007	ECT		
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